IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Priority Application Serial No					
Priority Filing Date					
Inventor	Zhongze Wang				
Assignee	Micron Technology, Inc.				
Priority Group Art Unit	2812				
Priority ExaminerJennifer M. Ke					
Attorney Docket No	MI22-2457				
Customer No	021567				
Title: Wafer Bonding Method of Forming	Silicon-on-Insulator Comprising				
Integrated Circuitry					

INFORMATION DISCLOSURE STATEMENT PURSUANT TO 37 C.F.R. §§ 1.56, 1.97 AND 1.98

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

The listed references were cited by, or submitted to, the Office in the parent, co-pending application of the above-identified application. The above-identified application is a divisional application of co-pending application Serial No. 10/340,126, filed January 10, 2003. Such prior disclosure is sufficient for the above-identified application as far as copies of the references are concerned. 37 C.F.R. § 1.98(d) and MPEP § 609(2).

Citation of these references is respectfully requested.

Respectfully submitted,

Dated: 12-12-63

Mark S. Matkin Reg. No. 32,268 Form PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. MI22-2457

PRIORITY SERIAL NO. 10/340,126

LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)

APPLICANT: Zhongze Wang

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U.S. PATEN	IT DOC	UMENTS						_		
*Examiner's Initials		Document Number	Date	Date Name		Class	Subclas		Filing Date If Appropriate	
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OTHER RE	FEREN	CES (including Autho	or, Title, Date, Pe	ertinent Pages, Etc.)						
	AM	Bernstein et al., Floating Body Effects, SOI DEVICE ELECTRICAL PROPERTIES 34-53 (pre-August 2001).								
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.